

Applicant: Ippei Shake et al.

Confirmation No.: 4422

Serial No.: 10/585,532

Att'y Docket No.: 14321.87

Filing Date: July 10, 2006

Art Unit: 2613

For: OPTICAL SIGNAL QUALITY MONITORING CIRCUIT AND OPTICAL SIGNAL
QUALITY MONITORING METHODSUPPLEMENTAL INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANTU.S. Patent Documents

Examiner <u>Initial*</u>	Document <u>Number</u>	Issue <u>Date</u>	Name
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Foreign Patent Documents

Examiner <u>Initial*</u>	Document <u>Number</u>	Publication <u>Date</u>	Country or <u>Patent Office</u>	<u>Translation</u>
____ 1	EP 1 363 423 A2	11/19/2003	Europe	N/A

Other Documents

(including author, title, pertinent pages, etc.)

Examiner
Initial*

____ 2 Office Action from Chinese Patent Office dated March 6, 2009 for corresponding Chinese Application No. 2005-80002207.1 which relates to the same invention as the present application.

References Cited by Applicants

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The reference designations "A1," "A2," etc. (referring to Applicant's reference 1, Applicant's reference 2, etc.) will be used by the Examiner in the same manner as Examiner's reference designations "A," "B," "C," etc. on Office Action Form PTO-1142.

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